## 4<sup>th</sup> International Workshop on Metrology for X-ray Optics, Mirror Design and Fabrication

The 4<sup>th</sup> International Workshop on Metrology for X-ray Optics, Mirror Design, and Fabrication will be held in Barcelona, Spain, as a satellite workshop of the Synchrotron Radiation and Instrumentation-SRI conference 2012. The workshop merges the fifth workshop on Active X-ray and XUV optics (ACTOP 2012) and the third International Workshop on Metrology for X-ray and XUV Optics. It will provide a forum for presentation and discussion on the latest developments in X-ray optics, with particular regard to improvements in metrology and results on deformable mirrors.

## Topics

- Fabrication and finishing technology for X-ray mirrors
- Metrology challenges for X-ray mirrors
- Active and adaptive optics for X-ray applications
- X-ray beam shaping, wave front optimization and coherence preservation
- In-situ metrology and wave front measurements
- · Optics for ultra-short/ultra-intense pulses
- Multilayer optics characterization and metrology
- Beamline performance and scientific results obtained by using novel optical schemes
- Specifications for optics at new storage ring and freeelectron laser sources
- Simulation and data analysis
- Theoretical framework for describing source coherence, and the propagation of mutual coherence, along with analytical- and numerical- modeling.
- Measurements of spatial and temporal coherence

International advisory committee Lahsen Assoufid (APS - USA) Daniele Cocco (SLAC - USA) Mourad Idir (NSLS-II - USA) Josep Nicolas (ALBA - Spain) *chair* Kawal Sawhney (Diamond - UK) Frank Siewert (HZB / BESSY-II - Germany) *co-Chair* Amparo Vivo (ESRF - France) Kazuto Yamauchi (Osaka University - Japan) Valeriy Yashchuk (LBNL - USA) *co-Chair* 

## Barcelona 4<sup>th</sup>-6<sup>th</sup> July 2012

## http://iwxm.cells.es/



